

# Vapor Crystal Growth and Characterization

ZnSe and Related II—VI Compound Semiconductors



Vapor Crystal Growth and Characterization

Ching-Hua Su

## Vapor Crystal Growth and Characterization

ZnSe and Related II–VI Compound Semiconductors



Ching-Hua Su Huntsville, AL, USA

ISBN 978-3-030-39654-1 ISBN 978-3-030-39655-8 (eBook) https://doi.org/10.1007/978-3-030-39655-8

#### © Springer Nature Switzerland AG 2020

This work is subject to copyright. All rights are reserved by the Publisher, whether the whole or part of the material is concerned, specifically the rights of translation, reprinting, reuse of illustrations, recitation, broadcasting, reproduction on microfilms or in any other physical way, and transmission or information storage and retrieval, electronic adaptation, computer software, or by similar or dissimilar methodology now known or hereafter developed.

The use of general descriptive names, registered names, trademarks, service marks, etc. in this publication does not imply, even in the absence of a specific statement, that such names are exempt from the relevant protective laws and regulations and therefore free for general use.

The publisher, the authors and the editors are safe to assume that the advice and information in this book are believed to be true and accurate at the date of publication. Neither the publisher nor the authors or the editors give a warranty, expressed or implied, with respect to the material contained herein or for any errors or omissions that may have been made. The publisher remains neutral with regard to jurisdictional claims in published maps and institutional affiliations.

This Springer imprint is published by the registered company Springer Nature Switzerland AG The registered company address is: Gewerbestrasse 11, 6330 Cham, Switzerland

For Wen-Jer Yu and Yuk Yin

#### Preface

With a simple processing setup, the crystal growth of physical vapor transport (PVT) transforms the original starting source material into the final form of crystal inside a closed ampoule. The vapor species are transported from the source at one end of the ampoule to form the crystal at the other end. The driving force for the transport is the pressure gradient between the source and the crystal ends created by an imposed temperature difference. Hence, the PVT process can be treated as three processes occurring in series:

- (1) The corresponding vapor species sublime from the source material at higher temperature,
- (2) The vapor species transport through the vapor phase to the crystal site at lower temperature, and
- (3) The condensation of vapor species on the crystal surface for its growth.

Besides its simplicity, crystallization by PVT has several advantages over the conventional melt growth. These advantages result mostly from (1) the lower processing temperatures, (2) the purification process associated with PVT, and (3) the improved surface morphology of the grown crystals. The high melting temperatures of the wide bandgap materials make the melt growth process very difficult to handle. For instance, in the Si–C binary system, the SiC compound melts at 2830 °C into Si-rich liquid and C solid, i.e., there is not even a stoichiometric melt of SiC to conduct melt growth at this extremely hot environment. The PVT process enables crystal growth at unique and advantageous environments than the melt growth would allow. The PVT process also acts as a purification process because of the differences in the vapor pressures of the native elements and the impurities. Additionally, most solid–vapor interfaces exhibit higher interfacial morphological stability during growth because of their low atomic roughness.

On the other hand, the main disadvantage of vapor growth techniques, compared to other growth techniques, is that the growth rates are low and inconsistent and the grown crystals are small with variable single crystal yields. To achieve a reasonable growth rate, an intrinsic requirement for the PVT process of multielements compounds is that the partial pressure of each element needs to be comparable to each other and at least above the level of  $10^{-4}$  atm under the growth conditions. This requirement excludes the possible PVT growth of III–V compounds because the equilibrium partial pressures of group III are usually orders of magnitude lower than those of the group V elements. It also excludes the PVT growth of any II–VI compounds consisting of oxygen and mercury due to their high pressures.

In this book, the PVT process will be focused on ZnSe-based materials, such as ZnSe, Cr- and Fe-doped ZnSe and ZnSeTe, as well as other wide bandgap II-VI compounds, such as CdTe, CdS, and ZnTe. The contents of the book are intended for the professional crystal growers, either academic researchers or commercial operators, by providing the details of the operating procedures and the theoretical bases behind them. After a short Introduction, Chap. 2 will present the fundamentals of PVT process, including partial pressure measurements and one-dimensional diffusion model for the transport of vapor species. The experimental measurements of the vapor transport rate, i.e., mass flux, as well as the heat treatments of the starting materials to maximize the mass flux for various material systems will be discussed in Chap. 3. The detailed crystal growth procedures and in situ real-time optical monitoring techniques will be given in Chap. 4. Chapters 5 and 6 will present the results of various characterization techniques, including morphology of the grown crystals, structural crystalline quality, impurity distribution, dopant levels, and optical properties. The measured results of thermal and electrical properties and the effects of post-growth annealing will be included in Chap. 7. The formulation and calculated results from two-dimensional and three-dimensional numerical simulation on the vapor transport process of ZnSe will be presented in Chap. 8.

Huntsville, USA

Ching-Hua Su

#### Acknowledgements

First of all, I would like to show my appreciation to my Ph.D. advisor, Prof. Robert F. Brebrick, who inspired and taught everything I know about compound semiconductors and was highly involved throughout the project. I am also indebted to my colleagues for their accomplishments to the project: Drs. A. Burger, M. Dudley, S. Feth, M. A. George, D. G. Gillies, S. L. Lehoczky, R. Matyi, K. Mazuruk, W. Palosz, N. Ramachandran, Yi-Gao Sha, F. R. Szofran, M. P. Volz, and Ling Jun Wang.

### Contents

1	Intr	Introduction 1   1.1 Group II–VI Wide Bandgap Compound Semiconductors 1					
	1.1						
	1.2	Crystal	llization by Physical Vapor Transport	3			
	References						
2	Fundamentals of Physical Vapor Transport Process						
	2.1	Sublimation of Source Materials					
		2.1.1	Vapor Pressures of Pure Elements	10			
		2.1.2	Thermodynamics of Solid and Vapor Phases				
			in Compound Semiconductors	11			
		2.1.3	Partial Pressure Measurements	15			
		2.1.4	Thermodynamic Analyses	24			
	2.2	Physic	al Vapor Transport Process (One-Dimensional				
		Diffusi	on Model)	26			
		2.2.1	Diffusive Transport in Binary Systems	26			
		2.2.2	Diffusive Transport in Multi-nary Systems	30			
		2.2.3	Diffusive Transport with Residual Gas of Impurities	31			
		2.2.4	Summary of One Dimensional Diffusion Analysis	33			
		2.2.5	Convective Transport	33			
	Appendix						
	References						
3	Vanor Transport Rate (Mass Flux) Measurements and Heat						
5	Treatments						
	3.1 Mass Flux of CdS by PVT						
	0.11	3.1.1	CdS Ampoules Sealed Under Vacuum	40			
		3.1.2	CdS Ampoules Sealed with Ar Pressure	44			
		3.1.3	CdS Samples Annealed Under Controlled				
			Cd Over-Pressure	46			
		3.1.4	Summary on PVT of CdS	47			
			•				

	3.2	Mass I	Flux and Heat Treatments of CdTe	48			
		3.2.1	Vapor Phase Stoichiometry	48			
		3.2.2	Heat Treatments of CdTe for PVT	49			
	3.3	Mass I	Flux and Heat Treatments for ZnSe System	53			
		3.3.1	In-Situ Dynamic Mass Flux Measurements	53			
		3.3.2	Heat Treatments of Source Materials	54			
		3.3.3	Measurements of Residual Gas Pressure				
			and Composition	56			
		3.3.4	Simultaneous Measurements of Partial Pressure				
			and Mass Flux in PVT of ZnSe	58			
		3.3.5	Optimum Heat Treatment Procedures for ZnSe				
			Starting Materials	60			
		3.3.6	Summary of Heat Treatment of Starting Material				
			of ZnSe	63			
	3.4	Mass I	Fluxes in ZnSe-Related Ternary Systems	64			
		3.4.1	One-Dimensional Diffusion Model for Ternary Case	64			
		3.4.2	Mass Flux of PVT for $ZnSe_{1-x}Te_x$ System	65			
		3.4.3	Mass Flux of PVT for $ZnSe_{1-x}S_x$ System	67			
		3.4.4	Mass Flux of Zn <sub>1-x</sub> Cd <sub>x</sub> Se System from				
			One-Dimensional Diffusion Model	71			
		3.4.5	Summary of Mass Flux of ZnSe-Related Ternary				
			Systems	71			
	References						
1	Crystal Crowth 7						
	4 1	Growth Ampoule Prenarations					
	4.2	Heat Treatments of Starting Materials					
	43	Crystal Growth Environments					
	1.5	431	Temperature Profile	79			
		432	Growth Configurations	80			
		433	Crystal Growth of ZnSe by PVT	82			
		434	Crystal Growth of ZnSe Doped with Transition	02			
		ч.э.т	Metals by PVT	84			
		435	Crystal Growth of ZnSeTe by PVT	86			
		436	Crystal Growth of CdTe by PVT	88			
		437	Crystal Growth of CdS by PVT	90			
		438	Crystal Growth of ZnTe by PVT	91			
	44	In-situ	Real Time Ontical Monitoring During Growth	91			
	7.7	441	Ontical Absorption Measurements	92			
		442	Ontical Interferometry Measurements	94			
	45	Recent	Advancement on the Enhancement of Transport				
		Rate h	v PVT	101			
	Refe	eferences 10					
	non	nences .		100			